Description: Test setup in the anechoic chamber

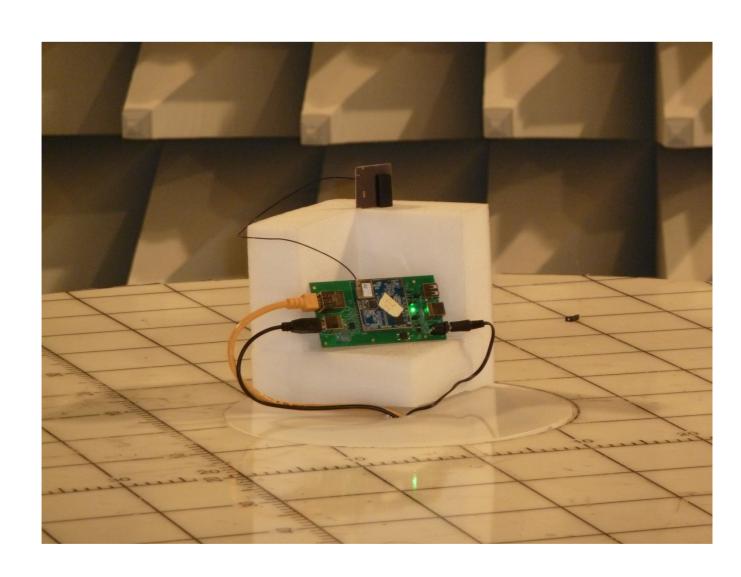
Division: Industry & Energy

Department: FG

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Description: Test setup below 30 MHz

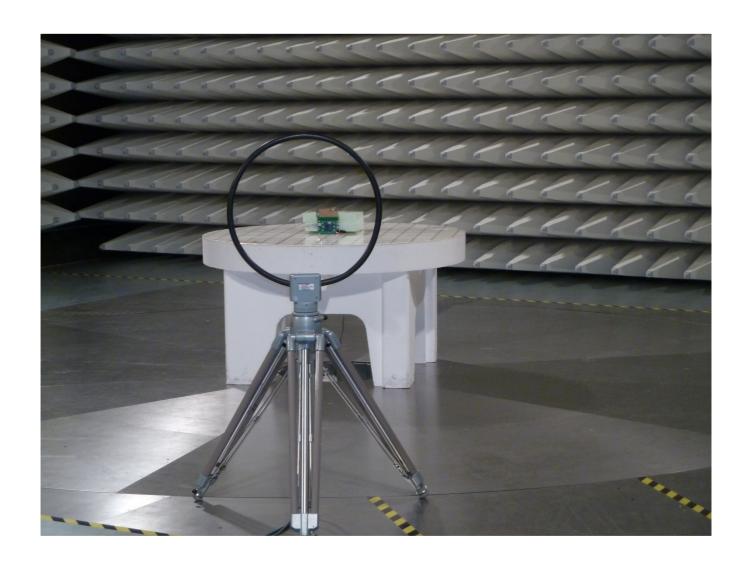
Division: Industry & Energy

Department: FG

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Description: Test setup 30-1000 MHz

Division: Industry & Energy

Department: FG

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Description: Test setup 1-18 GHz

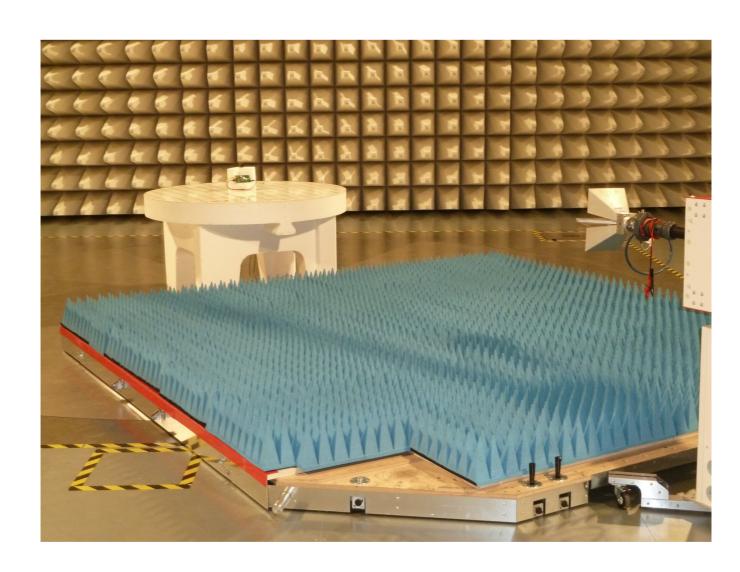
Division: Industry & Energy

Department: FG

Test report reference: INE-AT/FG-17/117

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Date: 19.06.2017



Description: Test setup above 18 GHz

Division: Industry & Energy

Department: FG

Test report reference: INE-AT/FG-17/117

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checked by: _____

